

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
Ben C. Wang		2196		

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*	B	US-7,039,902 b2	05-2006	Kuzmin et al.	717/126
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	M	US-			

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	V	The Concept of Dynamic Analysis, Thomas Ball, Oct. 1999, Bell Laboratories Lucent Technologies
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.